

M2M-0160-120D

Silicon Carbide Power MOSFET

N-Channel Enhancement Mode

Features

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive
- Avalanche Ruggedness
- Halogen Free, RoHS Compliant

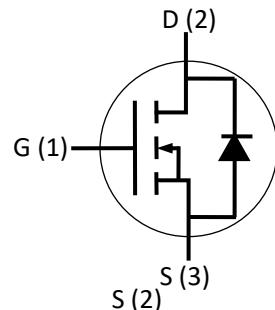
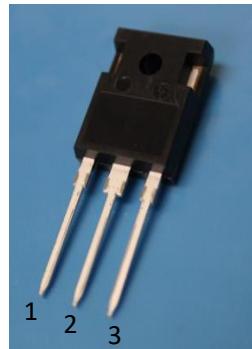
Benefits

- Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

Applications

- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC/DC Converters
- Battery Chargers
- Motor Drives
- Pulsed Power applications

Package



Part Number	Package
M2M-0160-120D	TO-247-3

Maximum Ratings ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
$V_{DS\max}$	Drain - Source Voltage	1200	V	$V_{GS}=0\text{V}, I_D=100\mu\text{A}$	
$V_{GS\max}$	Gate - Source Voltage	-10/+25	V	Absolute maximum values	
V_{GSop}	Gate - Source Voltage	-5/+20	V	Recommended operational values	
I_D	Continuous Drain Current	17 11	A	$V_{GS}=20\text{V}, T_c=25^\circ\text{C}$ $V_{GS}=20\text{V}, T_c=100^\circ\text{C}$	
I_{DM}	Pulse Drain Current	38	A	Pulse width limited by $T_{j\max}$	
P_D	Power Dissipation	127	W	$T_c=25^\circ\text{C}, T_j=150^\circ\text{C}$	Fig. 10
T_j, T_{stg}	Operating Junction and Storage Temperature	-55 to +150	°C		

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Electrical Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	1200			V	$V_{GS}=0V, I_D=100\mu A$	
$V_{GS(th)}$	Gate Threshold Voltage	2.0	2.4	4.0	V	$V_{GS} = V_{DS}, I_{DS}=2.5mA, T_c=25^\circ C$	Fig. 6
			1.8			$V_{GS} = V_{DS}, I_{DS}=2.5mA, T_c=150^\circ C$	
I_{DSS}	Zero Gate Voltage Drain Current		1	100	μA	$V_{DS}=1200V, V_{GS}=0V$	
I_{GSS}	Gate-Source Leakage Current		20	200	nA	$V_{GS}=20V, V_{DS}=0V$	
$R_{DS(on)}$	Drain-Source on-state Resistance		160	192	$m\Omega$	$V_{GS}=20V, I_D=10A, T_c=25^\circ C$	Fig. 4
			285			$V_{GS}=20V, I_D=10A, T_c=150^\circ C$	
g_{fs}	Transconductance		4.2		S	$V_{GS}=20V, I_D=10A, T_j=25^\circ C$	Fig. 5
			4.0			$V_{GS}=20V, I_D=10A, T_j=150^\circ C$	
C_{iss}	Input Capacitance		950		pF	$V_{GS}=0V, V_{DS}=1000V, f=1MHz$ $V_{AC}=25mV$	Fig. 8
C_{oss}	Output Capacitance		35.0				
C_{rss}	Reverse Transfer Capacitance		8.5				
E_{ON}	Turn-On Switching Energy		95		μJ	$V_{DS}=800V, V_{GS}=-5/20V, I_D=10A, R_{G(ext)}=2.5\Omega, L=256\mu H$	
E_{OFF}	Turn-Off Switching Energy		48				
$t_{d(on)}$	Turn-On Delay Time		12		ns	$V_{DD}=800V, V_{GS}=-5/20V$ $I_D=10A, R_{G(ext)}=2.5\Omega$, $R_L=80\Omega$, Timing relative to V_{DS}	
t_r	Rise Time		20				
$t_{d(off)}$	Turn-Off Delay Time		15				
t_f	Fall Time		10				
$R_{G(int)}$	Internal Gate Resistance		5.8		Ω	$f=1MHz, V_{AC}=25mV$	
Q_{gs}	Gate to Source Charge		9		nC	$V_{DD}=800V, V_{GS}=-5/20V$ $I_D=10A$	Fig. 9
Q_{gd}	Gate to Drain Charge		17				
Q_g	Total Gate Charge		42				

Reverse Diode Characteristics

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
V_{SD}	Diode Forward Voltage	3.5		V	$V_{GS} = -5V, I_{SD} = 5A, T_j = 25^\circ C$	Fig. 7
		3.3		V	$V_{GS} = -5V, I_{SD} = 5A, T_j = 150^\circ C$	
I_s	Continuous Diode Forward Current		17	A	$T_c = 25^\circ C$	
t_{rr}	Reverse Recovery time	14		ns	$V_{GS} = -5V, I_{SD} = 10A, V_R = 800V,$ $dif/dt = 1000A/\mu s;$	
Q_{rr}	Reverse Recovery Charge	44		nC		
I_{rrm}	Peak Reverse Recovery Current	6.0		A		

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Thermal Characteristics

Symbol	Parameter	Typ.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.98	°C/W		Fig. 11
$R_{\theta JA}$	Thermal Resistance From Junction to Ambient	40			

Typical Performance

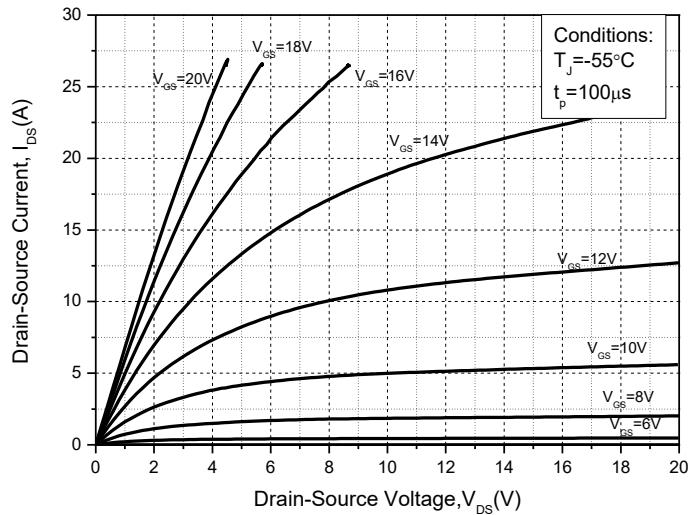


Figure 1. Output Characteristics $T_J = -55^\circ C$

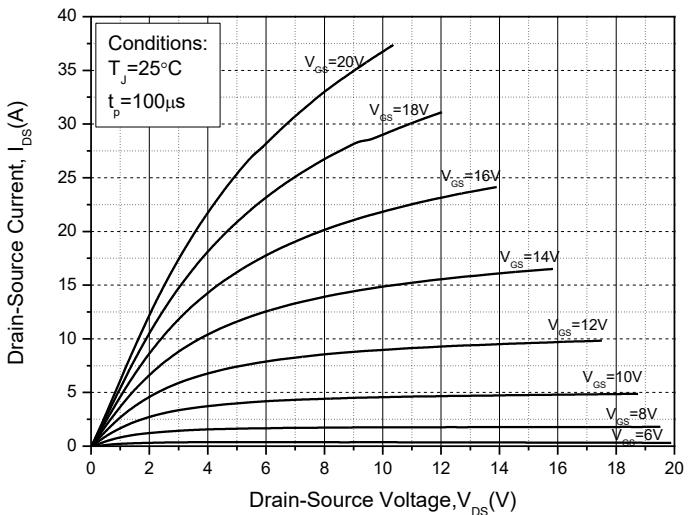


Figure 2. Output Characteristics $T_J = 25^\circ C$

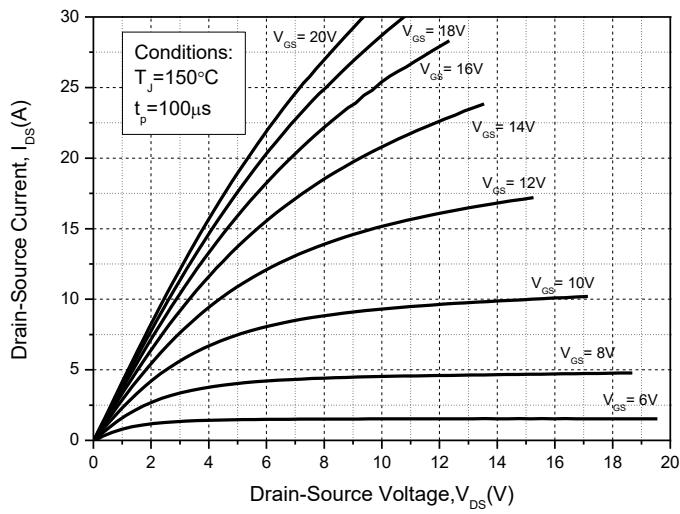


Figure 3. Output Characteristics $T_J = 150^\circ C$

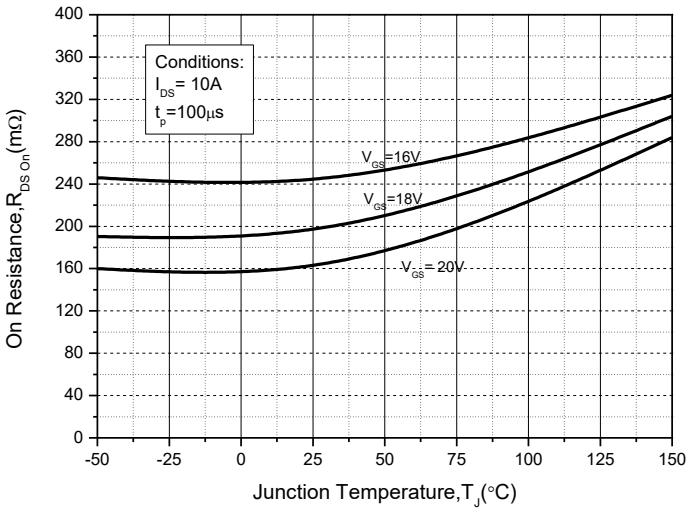


Figure 4. On-Resistance For Various Gate Voltage

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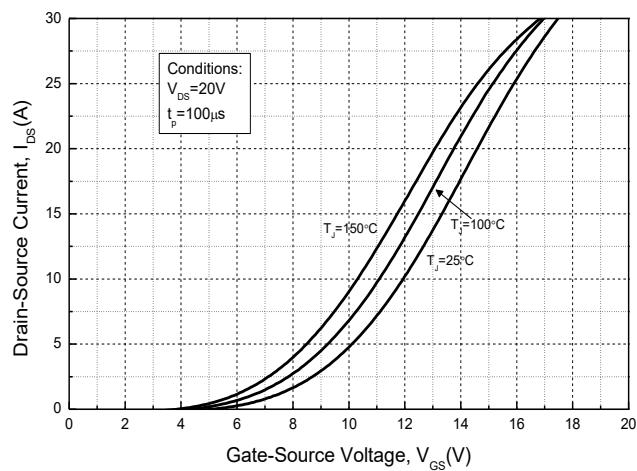


Figure 5. Transfer Characteristic
for Various Junction Temperatures

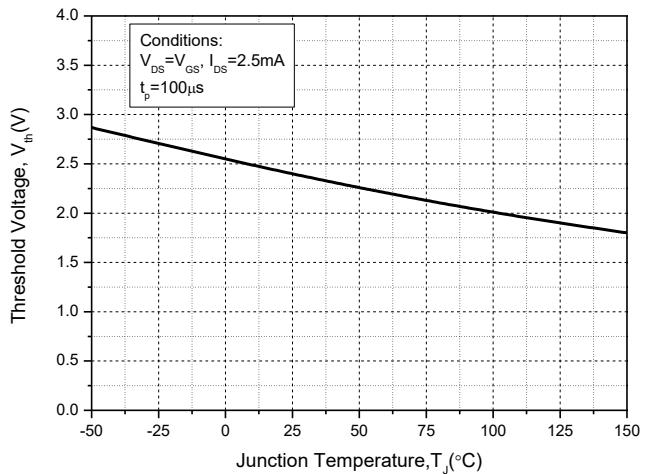


Figure 6. Threshold Voltage vs. Temperature

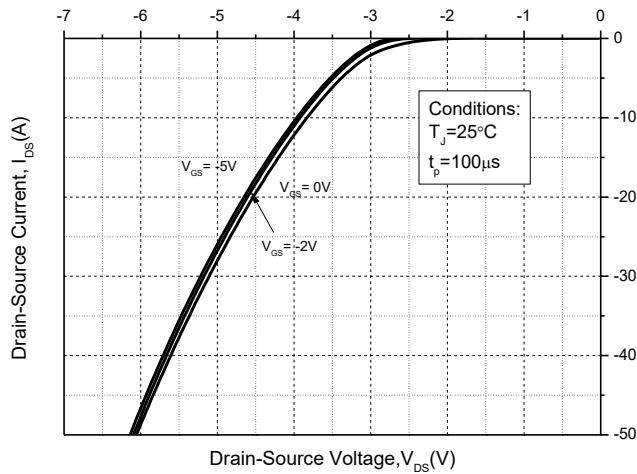


Figure 7. Body Diode Characteristics

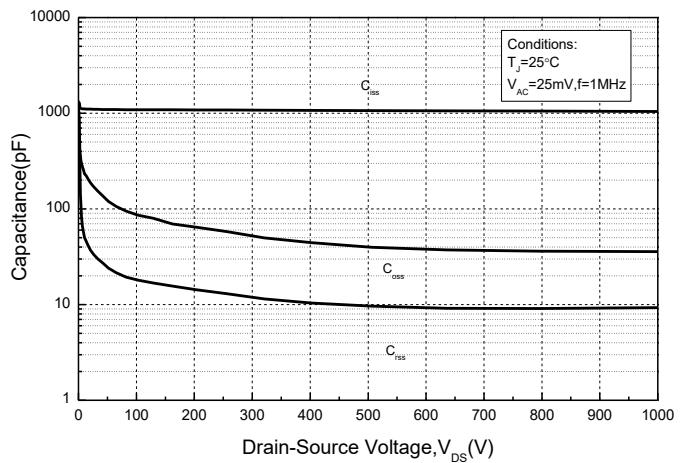


Figure 8. Capacitances vs. Drain-Source Voltage

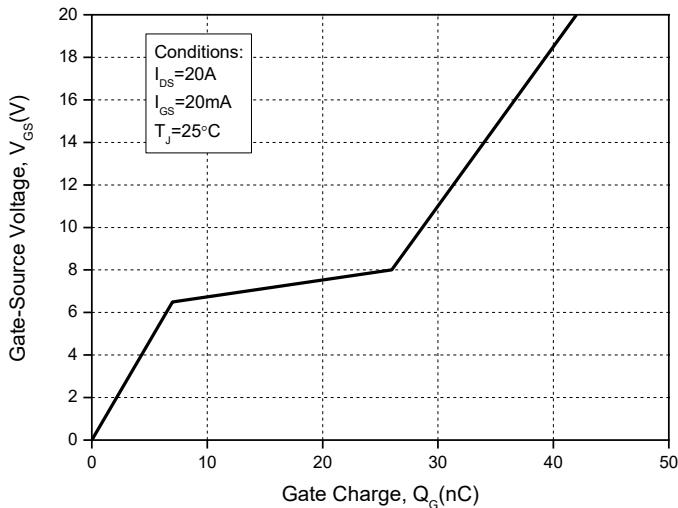


Figure 9. Gate Charge Characteristics

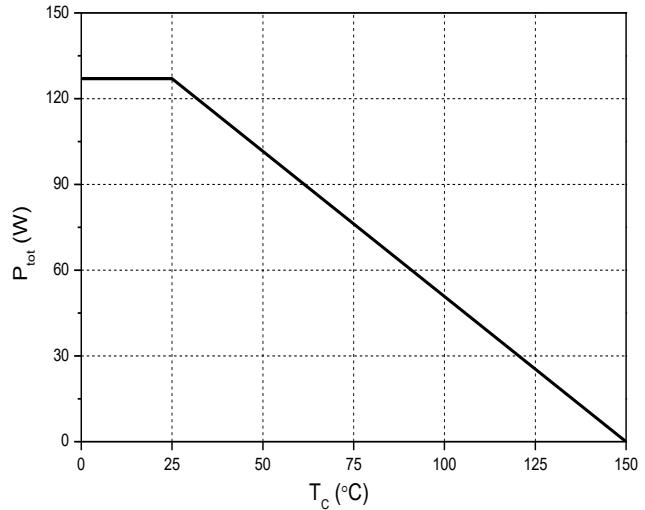


Figure 10. Power Dissipation Derating

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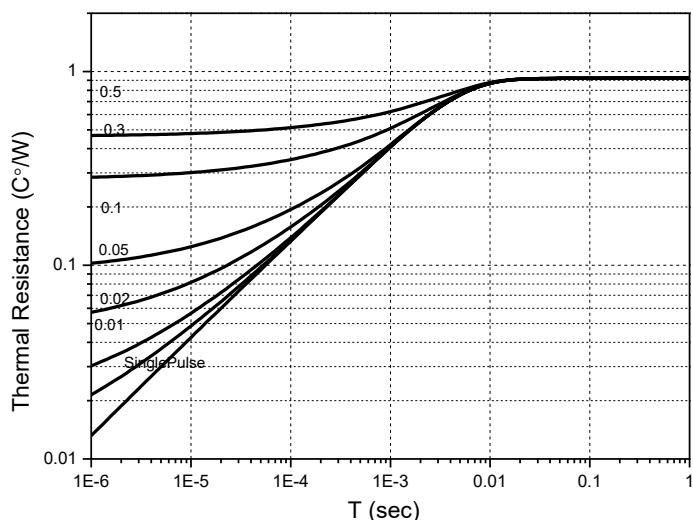


Figure 11. Transient Thermal Impedance

Package Dimensions: TO-247-3L

